



Specifically Designed for Computer and Switching Applications

Close parameter control and the JETEC TO-5 package assure device reliability and stable characteristics



ACTUAL SIZE

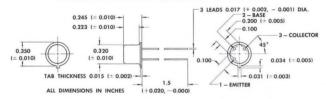
qualification testing

To assure maximum reliability, stability, and long life, all units are heat cycled from -55°C and room humidity to +75°C and 95% relative humidity for four complete cycles over an eight-hour period. All transistors are thoroughly tested for rigid adherence to specified design characteristics.

mechanical data

Welded case with glass-to-metal hermetic seal between case and leads. Unit weight is 1 gram.

THE BASE IS GROUNDED INTERNALLY TO THE CASE



absolute maximum ratings at 25°C case temperature

[except where advanced temperatures are indic	ated
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BV_{CBO}	Collector to Base	
	Emitter to Base	
	Collector to Emitter ($I_C = -0.6 \text{ mA}$)	
$I_{\mathbf{c}}$	Collector Current	1
	Total Dissipation (Derate 2.5 mW/°C for advanced temperatures) 150 mV	W
T_{j}	Collector Junction Temperature	
T_{A}	Storage Range	

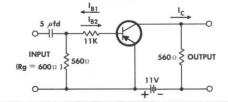
design chara

acteristics	at 25°C			min	design center	max	unit
ICBO IEBO BVCES hFE fαb VCE (SAT) VBE COb	Collector Reverse Current Emitter Reverse Current Collector to Emitter Voltage Forward Current Transfer Ratio Current Transfer Ratio Cutoff Frequency Saturation Voltage Input Voltage Output Capacitance	$I_{C} = -20 \text{mA}$	$\begin{array}{c} V_{CB} = -20V \\ V_{EB} = -10V \\ -0.4 \text{ mA} \\ V_{CB} = -5V \\ I_{B} = 1\text{ mA} \\ I_{B} = 1\text{ mA} \\ V_{CB} = -5V \end{array}$		2 30 100 8 0.11 0.33 13	6 6 - 200 - 0.2 -	μΑ μΑ V mc V V
h _{ib} h _{rb} h _{ob}	Input Impedance* Reverse Voltage Transfer Ratio* Output Admittance*	$\begin{array}{c} \text{I}_{\text{C}} = -1\text{mA} \\ \text{I}_{\text{C}} = -1\text{mA} \\ \text{I}_{\text{C}} = -1\text{mA} \end{array}$	$V_{CB} = -5V$ $V_{CB} = -5V$ $V_{CB} = -5V$	=	34 9 0.3	=	Ohm X10 ⁻⁴ µmho

^{*} Measured at 270 cps.

typical switching characteristics

TON	Turn On Time $(T_d + T_r)$	0.8 µsec
Ts	Storage Time	0.6 µsec
T_f	Fall Time	0.5 µsec



test currents

I _{B1}	=	-1.0 mA
I _{B2}	=	1.0 mA
lc.	=	-20 mA

LICENSED UNDER BELL SYSTEM PATENTS

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